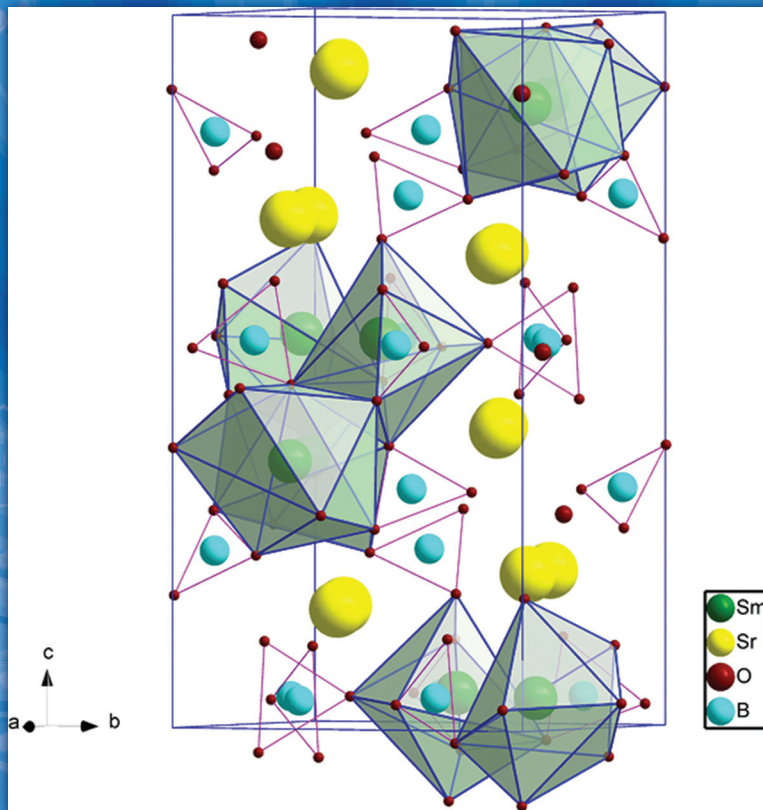


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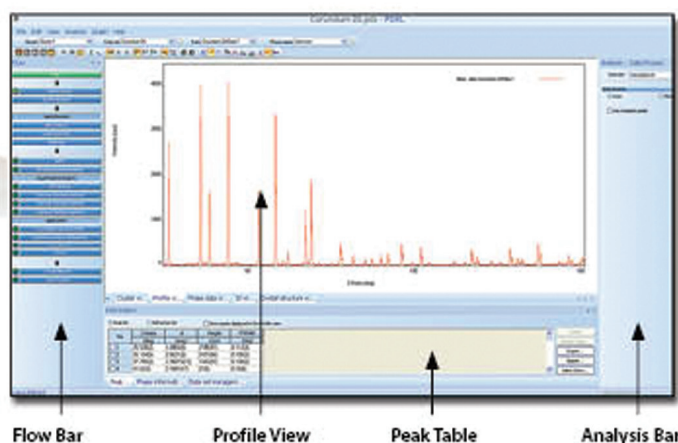


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Powder Diffraction

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On the Cover: View of the connection between distorted Sm-O polyhedra and triangular BO₃ groups. Large gray circles stand for Sr atoms, small gray circles for B atoms, small black circles for O atoms, and irregular polyhedra for Sm-O polyhedra (Courtesy of Jia-Yong Si and Ge-Mei Cai).

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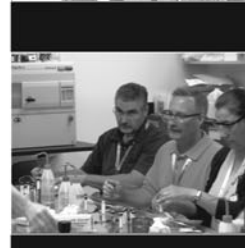
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